

| | Type | Hits | Search Text | DBs | Time Stamp | Comments | Error or Definiotion | Err or Definiotion | Ref # |
|----|------|------|---|---|---------------------|----------|----------------------|--------------------|-------|
| 1 | IS&R | 482 | (375/267) .CCLS. | US -PGPUB; USPAT; EPO; DERWENT | 2004/11/26 10:32 | | | | S1 |
| 2 | IS&R | 146 | (375/143) .CCLS. | US -PGPUB; USPAT; EPO; DERWENT | 2004/11/26 10:32 | | | | S2 |
| 3 | IS&R | 392 | (375/298) .CCLS. | US -PGPUB; USPAT; EPO; DERWENT | 2004/11/26 10:32 | | | | S3 |
| 4 | IS&R | 163 | (375/299) .CCLS. | US -PGPUB; USPAT; EPO; DERWENT | 2004/11/26 10:32 | | | | S4 |
| 5 | IS&R | 380 | (455/101) .CCLS. | US -PGPUB; USPAT; EPO; DERWENT | 2004/11/26 10:32 | | | | S5 |
| 6 | BRS | 0 | S6 and S1 | US -PGPUB; USPAT; EPO; DERWENT | 2004/11/26 10:34 | | | | S7 |
| 7 | BRS | 0 | S6 and S2 | US -PGPUB; USPAT; EPO; DERWENT | 2004/11/26 10:34 | | | | S8 |
| 8 | BRS | 1 | S6 and S3 | US -PGPUB; USPAT; EPO; DERWENT | 2004/11/26 10:35 | | | | S9 |
| 9 | BRS | 0 | S6 and S4 | US -PGPUB; USPAT; EPO; DERWENT | 2004/11/26 10:35 | | | | S10 |
| 10 | BRS | 21 | detect\$3 same demodulat\$3 same complex same sequence same multiply\$3 | US -PGPUB; USPAT; EPO; DERWENT | 2004/11/26 10:53 | | | | S6 |
| 11 | IS&R | 1 | ("6243561") .PN. | US -PGPUB; USPAT | 2004/11/26 10:53 | | | | S11 |

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